MITEC GROUP

Microtechnology and Instrumentation for Thermal and Electromagnetic Characterization

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FLEXIBLE SUBSTRATES CHARACTERIZATION

Experimental measured

Complex permittivity measurement

ntal measurements on polydimethylsilo (PDMS) substrate (up to 220 GHz)



erimental measurements on polydimethylsiloxane (PDMS) substrate for different temperatures

Thermal conductivity measurement

Three Omega Method: Due to joule's heating, temperature oscillations are produced at 2ω . Consequently fluctuations in the line heater resistance are produced. This leads to a third harmonic voltage $V_{3\omega}$. The slope of the curve $V_{3\omega}$ =f(ln(2 ω)) enables to determine the the conductivity





MICROWAVE & MM-WAVE SENSING APPLICATIONS

Innovative solutions based on Six-port Technology



Interferometric Scanning Microwave Microscopy



Freq : 1-20 GHz Resolution : < 1aF Course : 25 × 25 cm² Resolution : 0.1 µm Mode : Probing – Contactless 1-20 GH



Within IEMN

Involvement in three IEMN Flagships

30 60 90 120 160 180 210

"Nano-characterization" "Flexible Electronics"





30 60 90 120 150 180 Frequency (GHz)



MAIN COLLABORATIONS

National level

Univ. Artois - LAMH ESTIT - HEI Lille Hospital (CHRU) Univ. du Mans Univ. Reims - DTI Ecole des Mines de Doua CEA-LITEN CRHEA (Sophia Antipolis) FOTON (Insa Rennes)

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RENATECH

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